

<b>Notice of References Cited</b>	Application/Control No. 10/718,561	Applicant(s)/Patent Under Reexamination BAEK ET AL.	
	Examiner Leslie J. Evanisko	Art Unit 2854	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0081095	05-2003	Yi et al.	347/101
*	B	US-5,201,268	04-1993	Yamamoto et al.	101/170
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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